



Microstructural Characterization of Materials

By David G. Brandon, Wayne D. Kaplan

John Wiley and Sons Ltd, United States, 2008. Paperback. Book Condition: New. 2nd Revised edition. 244 x 158 mm. Language: English . Brand New Book. Microstructural characterization is usually achieved by allowing some form of probe to interact with a carefully prepared specimen. The most commonly used probes are visible light, X-ray radiation, a high-energy electron beam, or a sharp, flexible needle. These four types of probe form the basis for optical microscopy, X-ray diffraction, electron microscopy, and scanning probe microscopy. Microstructural Characterization of Materials, 2nd Edition is an introduction to the expertise involved in assessing the microstructure of engineering materials and to the experimental methods used for this purpose. Similar to the first edition, this 2nd edition explores the methodology of materials characterization under the three headings of crystal structure, microstructural morphology, and microanalysis. The principal methods of characterization, including diffraction analysis, optical microscopy, electron microscopy, and chemical microanalytical techniques are treated both qualitatively and quantitatively. An additional chapter has been added to the new edition to cover surface probe microscopy, and there are new sections on digital image recording and analysis, orientation imaging microscopy, focused ion-beam instruments, atom-probe microscopy, and 3-D image reconstruction. As well as being fully...



Reviews

This publication may be really worth a go through, and a lot better than other. It really is writter in simple terms and never difficult to understand. Once you begin to read the book, it is extremely difficult to leave it before concluding.

-- Natalie Abbott

This book will not be simple to get going on reading but extremely exciting to read through. Yes, it can be play, still an interesting and amazing literature. I am very easily could possibly get a delight of reading a written book.

-- Rene Olson